

INFORMATION DISCLOSURE CITATION <i>(Use several sheets if necessary)</i>	Docket Number (Optional) TWI-30730	Application Number NEW 10/796,322
	Applicant(s) Adam Norton et al.	
	Filing Date HEREWITH	Group Art Unit Unknown 2877

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE
<i>FC</i>	*AA	4,776,695	10/11/1988	van Pham et al.	356	328	09/02/1986
<i>FC</i>	*AB	5,659,397	08/19/1997	Miller et al.	356	446	06/08/1995
<i>FC</i>	*AC	5,747,813	05/05/1998	Norton et al.	250	372	04/14/1994
<i>FC</i>	*AD	US 2002/0021441	02/21/2002	Norton et al.	356	326	08/17/2001

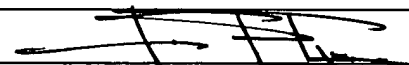
FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
<i>FC</i>	*AE	57-106846	07/02/1982	Japan (w/English abstract)	G01N	21/62	X	
<i>FC</i>	*AF	WO 00/57127	09/28/2000	PCT	G01B	11/06		

OTHER DOCUMENTS

(Including Author, Title, Date, Pertinent Pages, Etc.)

<i>FC</i>	*AG	K. Goto et al., "On-line System for Measuring Thickness of Hydrated Chromium Oxide Film on Tin Free Steel," <i>Iron and Steel</i> , Issue 9, 1984, pp. 1088-1094. (includes translation)						
<i>FC</i>	*AH	G. Harbeke et al., "Rapid Characterization of Polysilicon Films by Means of a UV Reflectometer," <i>RCA Review</i> , Vol. 44, March 1983, pp. 19-29.						

Examiner 	Date Considered 8-2004
Examiner: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	